

METHOD AND SYSTEM FOR TESTING AN ELECTRONIC DEVICE

ABSTRACT OF THE DISCLOSURE

According to one embodiment of the invention, a method for testing a device is provided. The method includes testing an electronic device having a first operating  
5 frequency by a tester device having a second operating frequency. The method also includes determining, during the test, a frequency difference between the first operating frequency and the second operating frequency. The method also includes initiating an equalization of the  
10 first and the second operating frequencies using a signal indicative of the frequency difference.

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